SELECT Annual Meeting and Technology Showcase – Logan, Utah – September 27-28, 2016

PURDUE UNIVERSITY

Equivalent Circuits for Analysis of

Common-Mode Behavior in Power Electronic-Based Systems*



Sustainable Electrified Transportation Center Utah State University

Michael R. Hayashi, Graduate Research Assistant, Purdue University-West Lafayette Steven D. Pekarek, Professor of Electrical and Computer Engineering, Purdue University-West Lafayette

INTRODUCTION

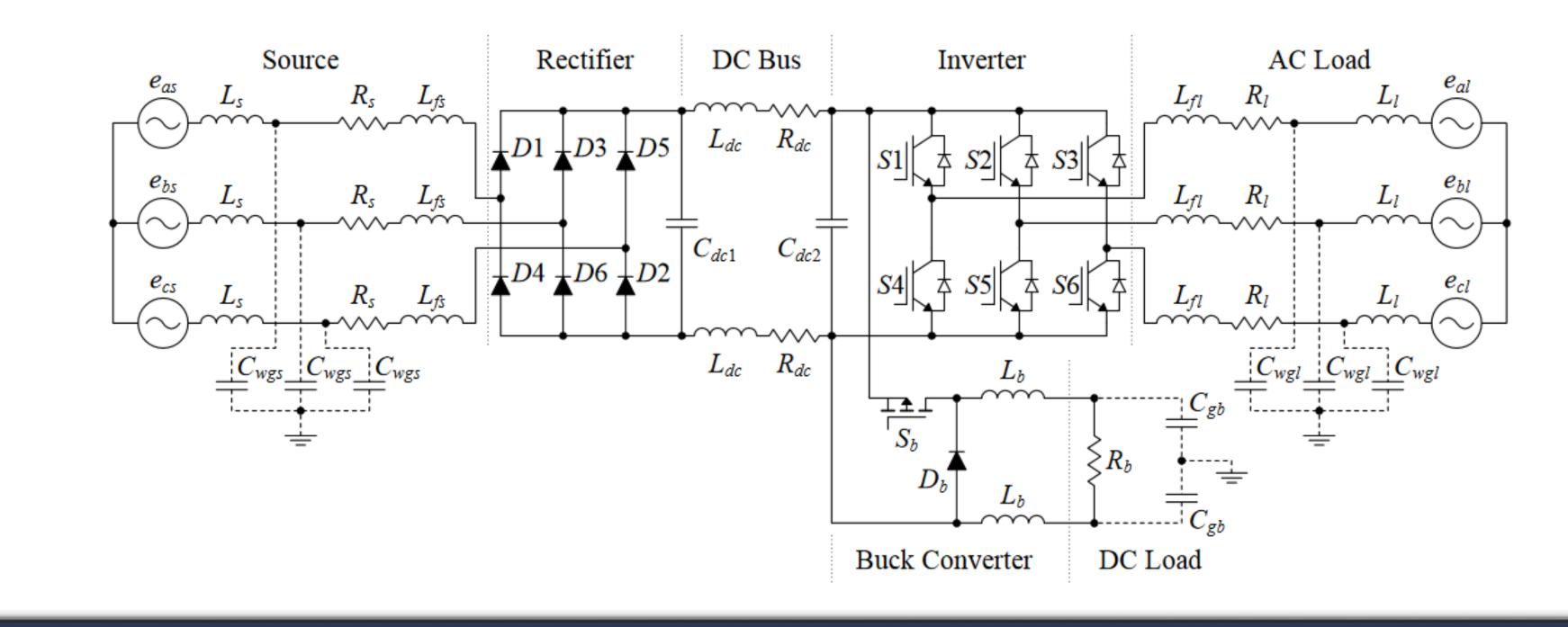
- Push toward higher switching frequencies and higher DC bus voltages has introduced challenges in electric vehicle design.
- Common-mode current can yield radiated emissions that couple to other systems, creating electromagnetic compatibility issues.
- Traditional approach to model common-mode behavior adds parasitic elements to differential-mode circuits
- Computational burden significant. Yields limited insight on how
- A formalized method to model common-mode behavior has been derived. A key contribution is the definition of a common-mode voltage with respect to arbitrary point P (not ground).
- One can characterize components separately, then connect through selection of the point P.
- Yields simplified model with lower computational burden and capability to provide better insight into problematic resonances, influence of switching frequency, etc.

to proceed.

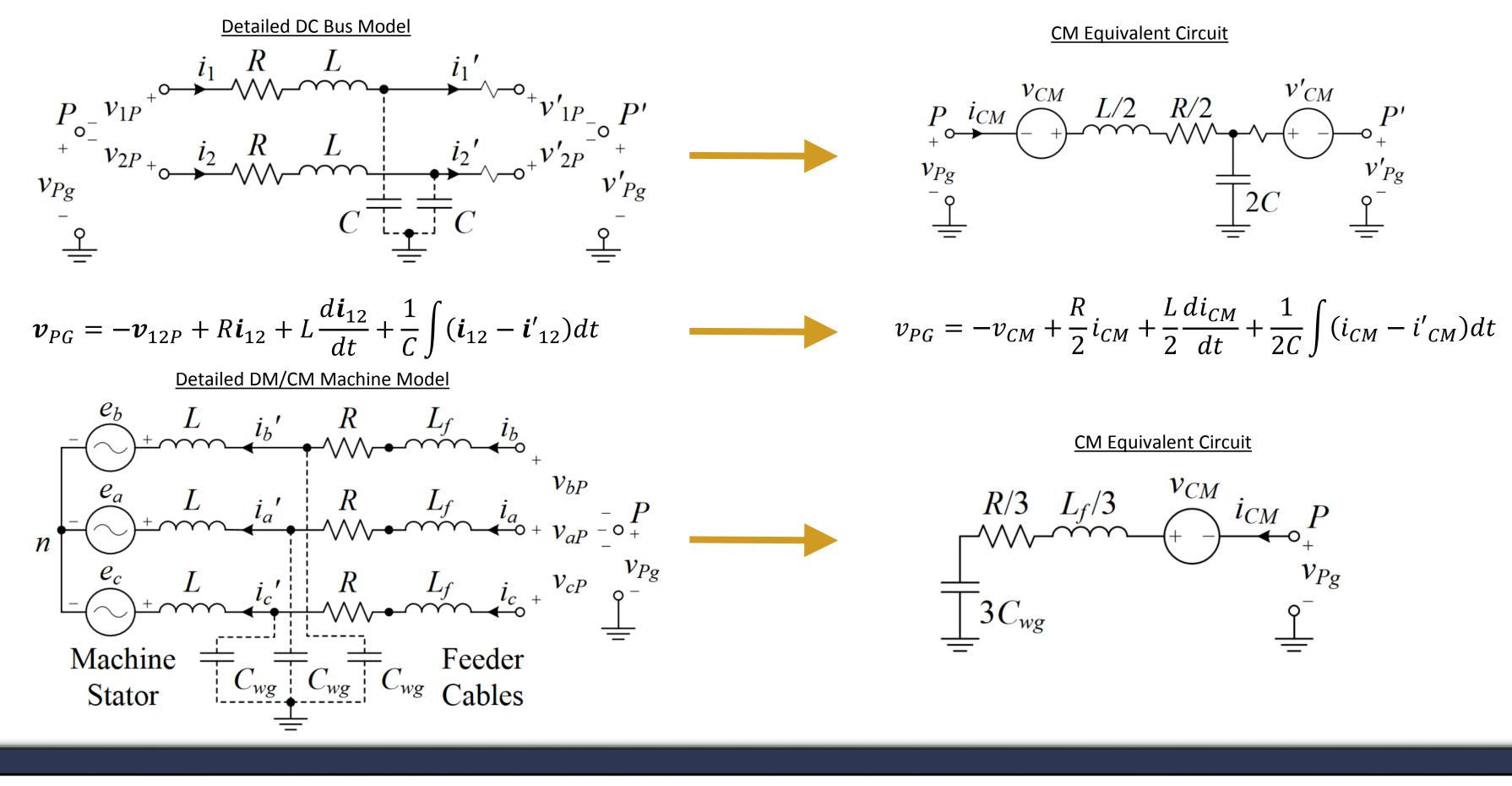
Easier to identify effectiveness of mitigation steps.

ADDING PARASITIC ELEMENTS

Types of common-mode problems encountered and desired fidelity of model will affect what parasitic pathways need to be added to form the mixed-mode circuit.

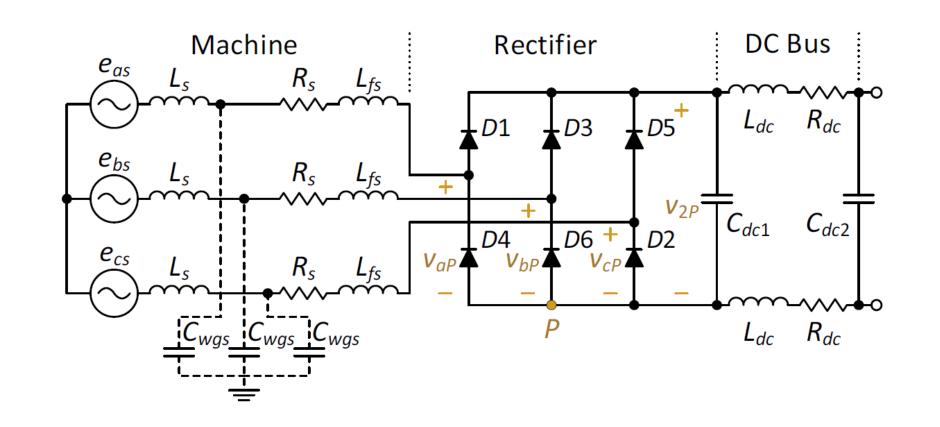


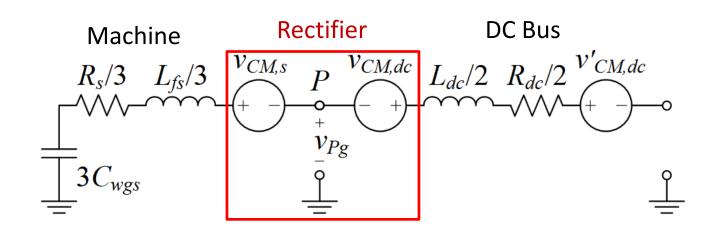
DERIVING COMMON-MODE EQUIVALENT CIRCUIT



FORMING COMMON-MODE CIRCUITS OF SYSTEMS

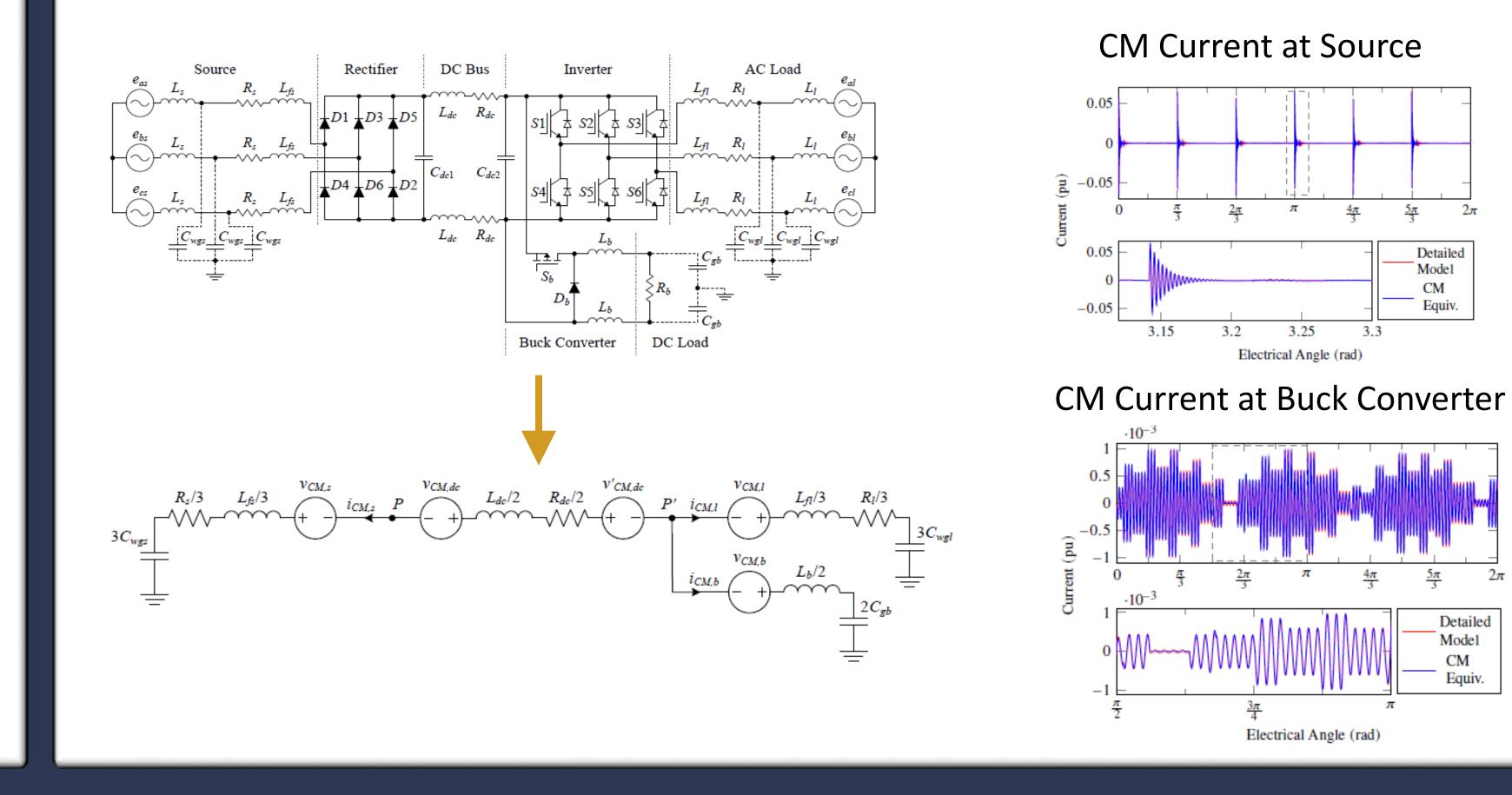
Select shared reference point and connect CM equivalent circuits.

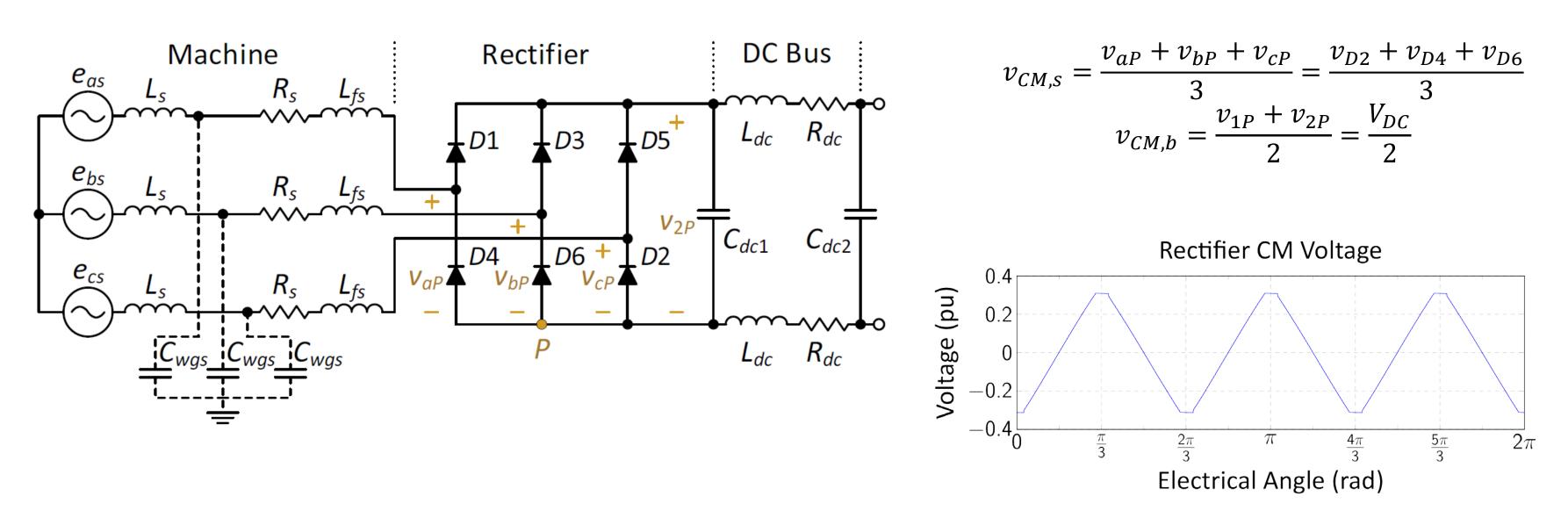




CHARACTERIZING COMMON-MODE SOURCES

VALIDATION OF APPROACH





* A. D. Brovont and S. D. Pekarek, "Equivalent circuits for common-mode analysis of naval power systems," *Electric Ship Technologies Symposium (ESTS), 2015 IEEE*, Alexandria, VA, 2015, pp. 245-250.